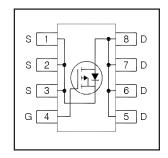
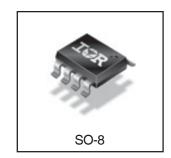


# IRF9321PbF

# HEXFET® Power MOSFET

V <sub>DS</sub>	-30	٧
$R_{DS(on) max}$ (@V <sub>GS</sub> = -10V)	7.2	$\mathbf{m}\Omega$
<b>R</b> <sub>DS(on) max</sub> (@V <sub>GS</sub> = -4.5V)	11.2	$\mathbf{m}\Omega$
Q <sub>g (typical)</sub>	34	nC
<b>I</b> <sub>D</sub> (@T <sub>A</sub> = 25°C)	-15	A





## **Applications**

• Charge and Discharge Switch for Notebook PC Battery Application

## **Features and Benefits**

**Features** 

Industry-Standard SO-8 Package
RoHS Compliant Containing no Lead, no Bromide and no Halogen

**Resulting Benefits** 

results in Multi-Vendor Compatibility

⇒ Environmentally Friendlier

Orderable part number	Package Type	Standard Pack		Note
_		Form	Quantity	
IRF9321PbF	SO8	Tube/Bulk	95	
IRF9321TRPbF	SO8	Tape and Reel	4000	

**Absolute Maximum Ratings** 

	Parameter	Max.	Units
V <sub>DS</sub>	Drain-to-Source Voltage	-30	V
V <sub>GS</sub>	Gate-to-Source Voltage	±20	
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ -10V	-15	
I <sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ -10V	-12	А
I <sub>DM</sub>	Pulsed Drain Current ①	-120	
P <sub>D</sub> @T <sub>A</sub> = 25°C	Power Dissipation ④	2.5	W
P <sub>D</sub> @T <sub>A</sub> = 70°C	Power Dissipation ④	1.6	VV
	Linear Derating Factor	0.02	W/°C
T <sub>J</sub>	Operating Junction and	-55 to + 150	°C
T <sub>STG</sub>	Storage Temperature Range		

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# Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	-30			V	$V_{GS} = 0V, I_D = -250\mu A$
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.021		V/°C	Reference to 25°C, I <sub>D</sub> = -1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		5.9	7.2	0	V <sub>GS</sub> = -10V, I <sub>D</sub> = -15A ③
	Static Diam-to-Source On-Resistance		9.3	11.2	mΩ	V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -12A ③
$V_{GS(th)}$	Gate Threshold Voltage	-1.3	-1.8	-2.4	V	$V_{DS} = V_{GS}$ , $I_D = -50\mu A$
$\Delta V_{GS(th)}$	Gate Threshold Voltage Coefficient		-5.9		mV/°C	
I <sub>DSS</sub>	Drain-to-Source Leakage Current			-1.0		$V_{DS} = -24V, V_{GS} = 0V$
				-150	μΑ	$V_{DS} = -24V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			-100	nA	V <sub>GS</sub> = -20V
	Gate-to-Source Reverse Leakage			100	TIA.	V <sub>GS</sub> = 20V
gfs	Forward Transconductance	30			S	$V_{DS} = -10V, I_D = -12A$
$Q_g$	Total Gate Charge ©		34		nC	$V_{DS} = -15V, V_{GS} = -4.5V, I_{D} = -12A$
$Q_g$	Total Gate Charge ©		65	98		V <sub>GS</sub> = -10V
$Q_{gs}$	Gate-to-Source Charge ®		10		nC	V <sub>DS</sub> = -15V
$Q_{gd}$	Gate-to-Drain Charge ©		16		Ī	I <sub>D</sub> = -12A
$R_G$	Gate Resistance ®		18		Ω	
t <sub>d(on)</sub>	Turn-On Delay Time		21			$V_{DD} = -30V, V_{GS} = -4.5V$ ③
t <sub>r</sub>	Rise Time		79		ns	I <sub>D</sub> = -1.0A
$t_{d(off)}$	Turn-Off Delay Time		185		115	$R_G = 6.8\Omega$
t <sub>f</sub>	Fall Time		145			See Figs. 19a & 19b
C <sub>iss</sub>	Input Capacitance		2590			$V_{GS} = 0V$
C <sub>oss</sub>	Output Capacitance		590		pF	V <sub>DS</sub> = -25V
C <sub>rss</sub>	Reverse Transfer Capacitance	_	360		<u> </u>	f = 1.0MHz

## **Avalanche Characteristics**

	Parameter	Тур.	Max.	Units
E <sub>AS</sub>	Single Pulse Avalanche Energy ②		310	mJ
I <sub>AR</sub>	Avalanche Current ①		-12	Α

## **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			-2.5		MOSFET symbol
	(Body Diode)			-2.5		showing the
I <sub>SM</sub>	Pulsed Source Current			-120	A	integral reverse
	(Body Diode) ①			-120		p-n junction diode.
$V_{\text{SD}}$	Diode Forward Voltage			-1.2	V	$T_J = 25^{\circ}C$ , $I_S = -2.5A$ , $V_{GS} = 0V$ ③
t <sub>rr</sub>	Reverse Recovery Time		38	57	ns	$T_J = 25^{\circ}C$ , $I_F = -2.5A$ , $V_{DD} = -24V$
Q <sub>rr</sub>	Reverse Recovery Charge		24	36	nC	di/dt = 100/μs ③

## **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JL}$	Junction-to-Drain Lead ©		20	°C/W
$R_{\theta JA}$	Junction-to-Ambient @		50	C/VV

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting  $T_J = 25$ °C, L = 4.3mH,  $R_G = 25\Omega$ ,  $I_{AS} = -12$ A.
- $\ensuremath{\mathfrak{G}}$  When mounted on 1 inch square copper board.
- © For DESIGN AID ONLY, not subject to production testing.

2 www.irf.com

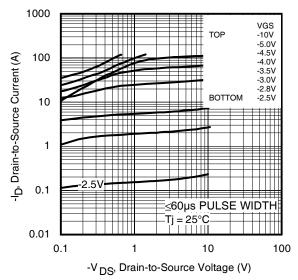


Fig 1. Typical Output Characteristics

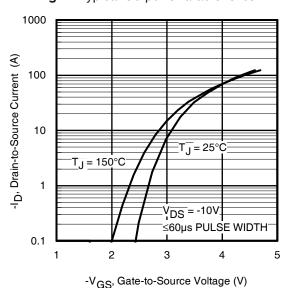
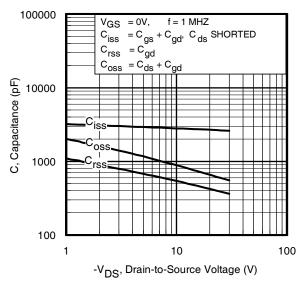


Fig 3. Typical Transfer Characteristics



**Fig 5.** Typical Capacitance vs.Drain-to-Source Voltage www.irf.com

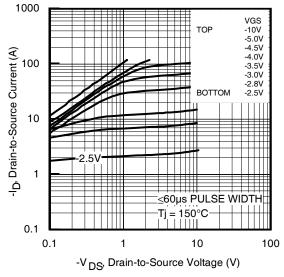


Fig 2. Typical Output Characteristics

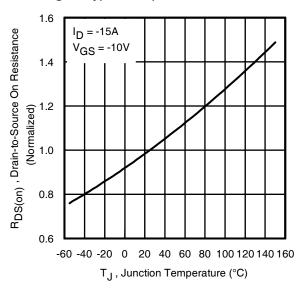


Fig 4. Normalized On-Resistance vs. Temperature

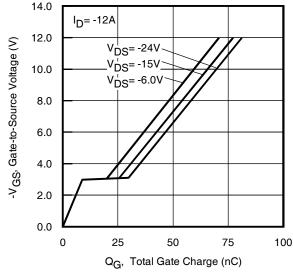


Fig 6. Typical Gate Charge vs.Gate-to-Source Voltage

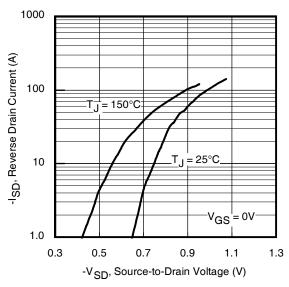
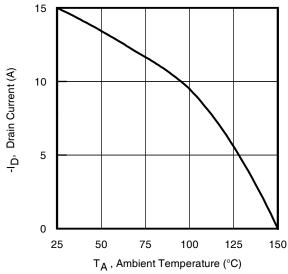


Fig 7. Typical Source-Drain Diode Forward Voltage



**Fig 9.** Maximum Drain Current vs. Ambient Temperature

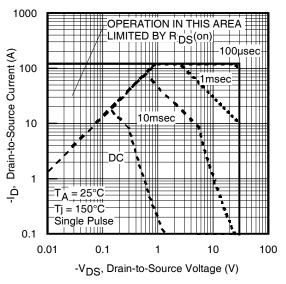


Fig 8. Maximum Safe Operating Area

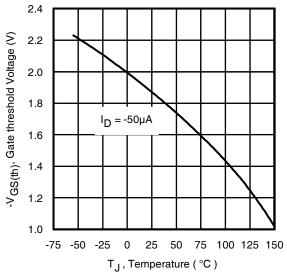


Fig 10. Threshold Voltage vs. Temperature

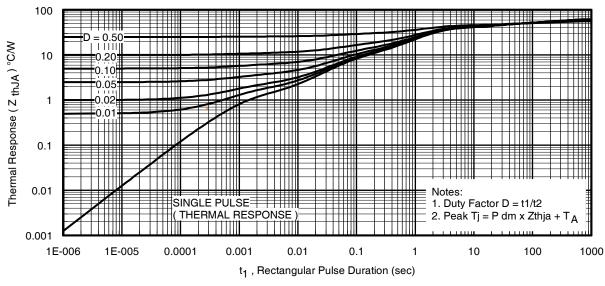


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

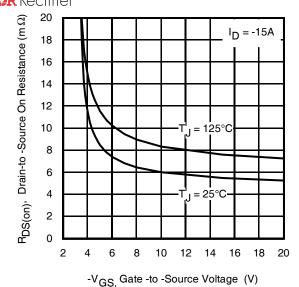


Fig 12. On-Resistance vs. Gate Voltage

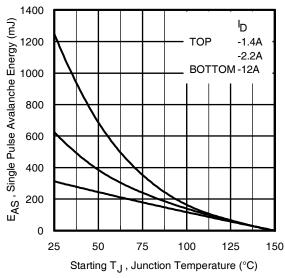


Fig 14. Maximum Avalanche Energy vs. Drain Current

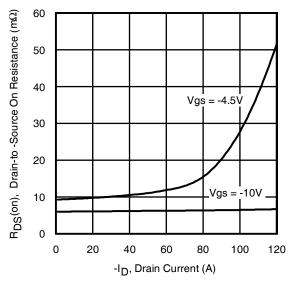


Fig 13. Typical On-Resistance vs. Drain Current

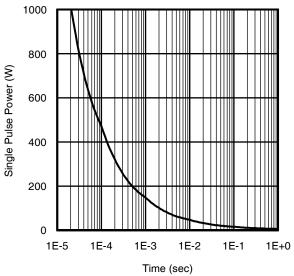
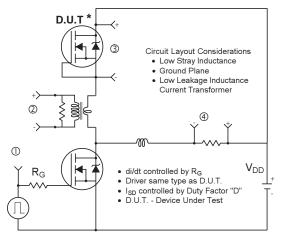
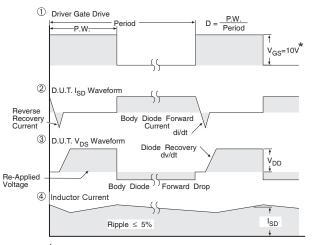


Fig 15. Typical Power vs. Time



<sup>\*</sup> Reverse Polarity of D.U.T for P-Channel



\* V<sub>GS</sub> = 5V for Logic Level Devices

Fig 16. Diode Reverse Recovery Test Circuit for P-Channel HEXFET® Power MOSFETs

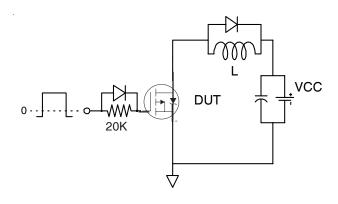


Fig 17a. Gate Charge Test Circuit

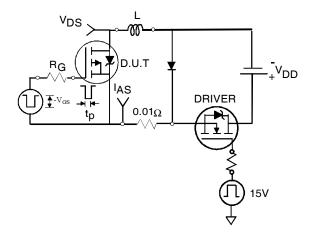


Fig 18a. Unclamped Inductive Test Circuit

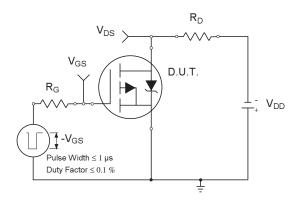


Fig 19a. Switching Time Test Circuit

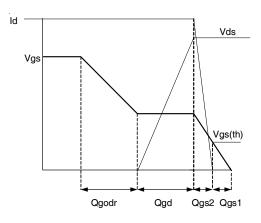


Fig 17b. Gate Charge Waveform

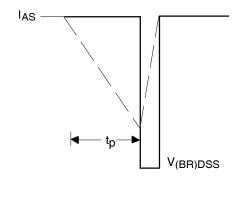


Fig 18b. Unclamped Inductive Waveforms

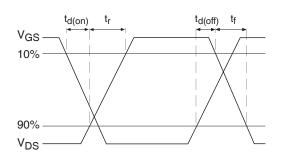
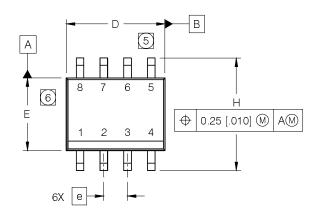


Fig 19b. Switching Time Waveforms

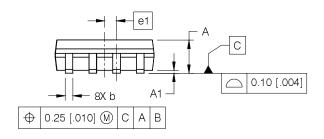
6 www.irf.com

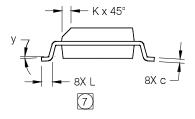
# SO-8 Package Outline(Mosfet & Fetky)

Dimensions are shown in milimeters (inches)



DIM	INC	HES	MILLIM	ETERS
INIIO	MIN	MAX	MIN	MAX
Α	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
С	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
е	.050 B	ASIC	1.27 BASIC	
e 1	.025 B/	ASIC	0.635 E	BASIC
Н	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
У	0°	8°	0°	8°





#### NOTES:

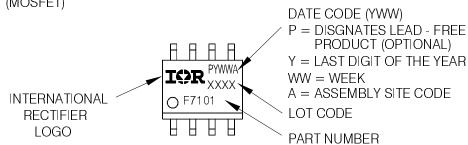
- 1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
- 2. CONTROLLING DIMENSION: MILLIMETER
- 3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
- (5) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.15 [.006].
- (6) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.25 [.010].
- DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE.

# 

7

# SO-8 Part Marking Information

EXAMPLE: THIS IS AN IRF7101 (MOSFET)

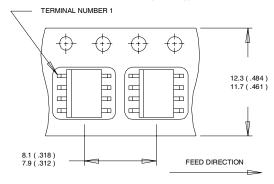


Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

# IRF9321PbF

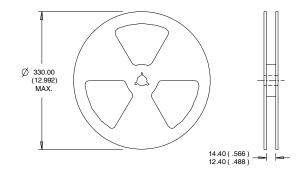


SO-8 Tape and Reel (Dimensions are shown in milimeters (inches))



#### NOTES:

- 1. CONTROLLING DIMENSION : MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

CONTROLLING DIMENSION : MILLIMETER.
 OUTLINE CONFORMS TO EIA-481 & EIA-541.

#### Qualification Information<sup>†</sup>

Qualification level	Consumer ††		
Qualification level	(per JEDEC JESD47F <sup>†††</sup> guidelines)		
Moisture Sensitivity Level	SO-8	MSL1 (per JEDEC J-STD-020D <sup>†††</sup> )	
RoHS Compliant	Yes		

- † Qualification standards can be found at International Rectifier's web site http://www.irf.com/product-info/reliability
- †† Higher qualification ratings may be available should the user have such requirements. Please contact your International Rectifier sales representative for further information: <a href="http://www.irf.com/whoto-call/salesrep/">http://www.irf.com/whoto-call/salesrep/</a>
- ††† Applicable version of JEDEC standard at the time of product release.

Data and specifications subject to change without notice.



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